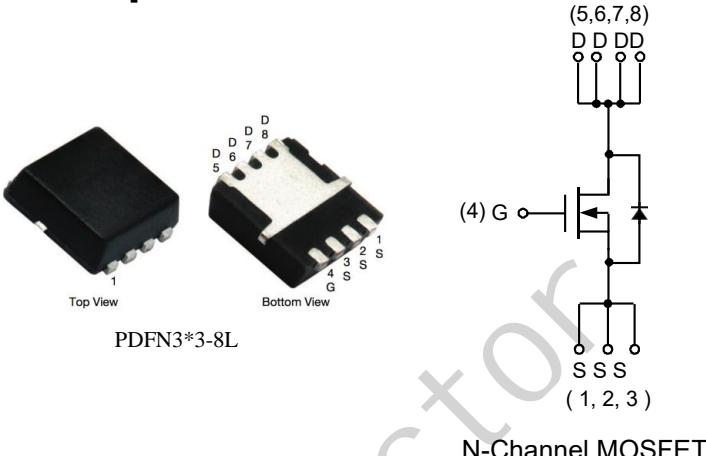


Features

- 30V/23A,
 - $R_{DS(ON)} = 16m\Omega(\text{typ.}) @ V_{GS} = 10V$
 - $R_{DS(ON)} = 21m\Omega(\text{typ.}) @ V_{GS} = 4.5V$
 - Provide Excellent $Q_{gd} \times R_{DS(ON)}$
 - 100% UIS + R_g Tested
 - Reliable and Rugged
 - Lead Free and Green Devices Available
(RoHS Compliant)

Pin Description



Applications

- Power Management in Notebook Computer, Portable Equipment and Battery Powered Systems.

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit
V_{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	± 20	
I_D^a	Continuous Drain Current ($V_{GS}=10V$)	$T_A=25^\circ C$	7
		$T_A=70^\circ C$	5.6
I_{DM}^a	Pulsed Drain Current ($V_{GS}=10V$)		28
I_D^c	Continuous Drain Current ($V_{GS}=10V$)	$T_C=25^\circ C$	23
		$T_C=70^\circ C$	19
I_S^a	Diode Continuous Forward Current		1.5
I_{AS}^b	Avalanche Current, Single pulse	$L=0.1mH$	13
		$L=0.5mH$	7
E_{AS}^b	Avalanche Energy, Single pulse	$L=0.1mH$	8.45
		$L=0.5mH$	12.25
T_J	Maximum Junction Temperature		150
T_{STG}	Storage Temperature Range		-55 to 150
P_D^a	Maximum Power Dissipation	$T_A=25^\circ C$	1.56
		$T_A=70^\circ C$	1
P_D^c	Maximum Power Dissipation	$T_C=25^\circ C$	17.8
		$T_C=70^\circ C$	11.4
$R_{\theta JA}^a$	Thermal Resistance-Junction to Ambient	$t \leq 10s$	50
		Steady State	80
$R_{\theta JC}^c$	Thermal Resistance-Junction to Case	Steady State	7

Note a: Surface Mounted on 1in² pad area. t < 10sec.

Note b: UIS tested and pulse width limited by maximum junction temperature 150°C (initial temperature $T_i=25^\circ\text{C}$).

Note c: The power dissipation P_D is based on $T_{J(MAX)} = 150^\circ\text{C}$, and it is useful for reducing junction-to-case thermal resistance (R_{AJC}) when additional heat sink is used.

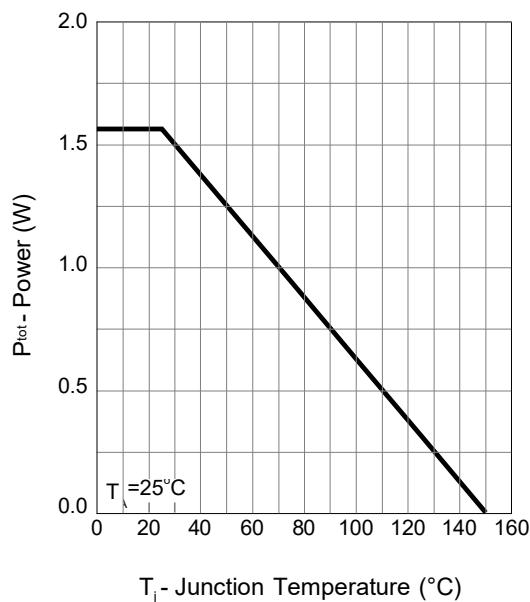
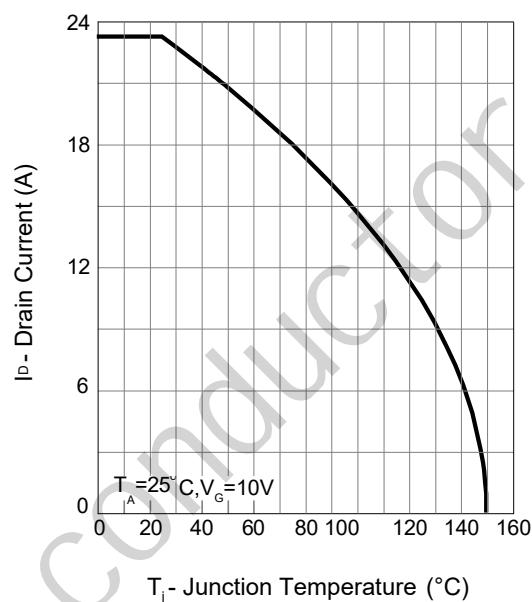
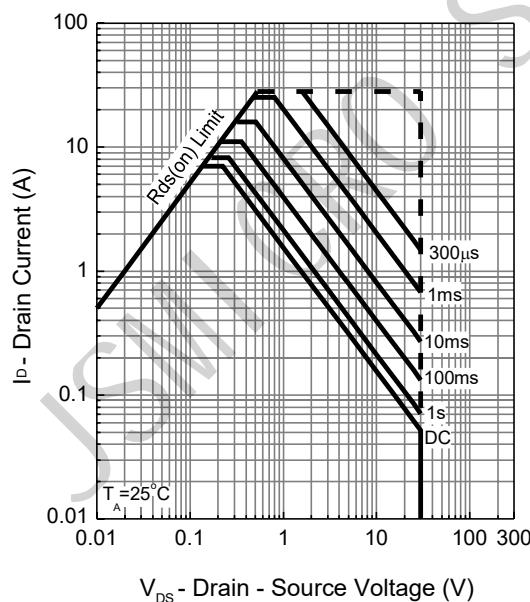
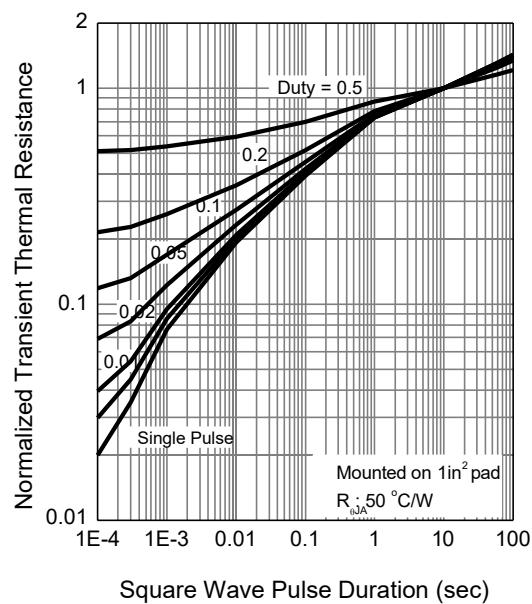
Electrical Characteristics ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_{\text{DS}}=250\mu\text{A}$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=24\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	μA
		$\text{T}_j=85^\circ\text{C}$	-	-	30	
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{DS}}=250\mu\text{A}$	1.0	1.8	2.5	V
I_{GSS}	Gate Leakage Current	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$\text{R}_{\text{DS(ON)}}^{\text{d}}$	Drain-Source On-state Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{DS}}=8\text{A}$	-	16	21	$\text{m}\Omega$
		$\text{T}_j=125^\circ\text{C}$	-	25.5	-	
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{DS}}=5\text{A}$	-	21	26	
Diode Characteristics						
$\text{V}_{\text{SD}}^{\text{d}}$	Diode Forward Voltage	$\text{I}_{\text{SD}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	0.75	1.1	V
t_{rr}^{e}	Reverse Recovery Time	$\text{I}_{\text{SD}}=8\text{A}, \frac{d\text{I}_{\text{SD}}}{dt}=100\text{A}/\mu\text{s}$	-	12	-	ns
t_a	Charge Time		-	6.2	-	
t_b	Discharge Time		-	5.8	-	
Q_{rr}^{e}	Reverse Recovery Charge		-	3.7	-	
Dynamic Characteristics ^e						
R_G	Gate Resistance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=0\text{V}, \text{F}=1\text{MHz}$	1	1.5	3	Ω
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{Frequency}=1.0\text{MHz}$	300	415	550	pF
C_{oss}	Output Capacitance		50	70	100	
C_{rss}	Reverse Transfer Capacitance		30	40	60	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$\text{V}_{\text{DD}}=15\text{V}, \text{R}_L=15\Omega, \text{I}_{\text{DS}}=1\text{A}, \text{V}_{\text{GEN}}=10\text{V}, \text{R}_G=6\Omega$	-	5.5	9	ns
t_r	Turn-on Rise Time		-	9	18	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	14	25	
t_f	Turn-off Fall Time		-	3.6	7	
Gate Charge Characteristics ^e						
Q_g	Total Gate Charge	$\text{V}_{\text{DS}}=15\text{V}, \text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{DS}}=8\text{A}$	-	3.8	5.5	nC
Q_g	Total Gate Charge	$\text{V}_{\text{DS}}=15\text{V}, \text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{DS}}=8\text{A}$	-	8	13	
Q_{gth}	Threshold Gate Charge		-	0.4	0.7	
Q_{gs}	Gate-Source Charge		-	1.1	1.8	
Q_{gd}	Gate-Drain Charge		-	1.6	2.1	

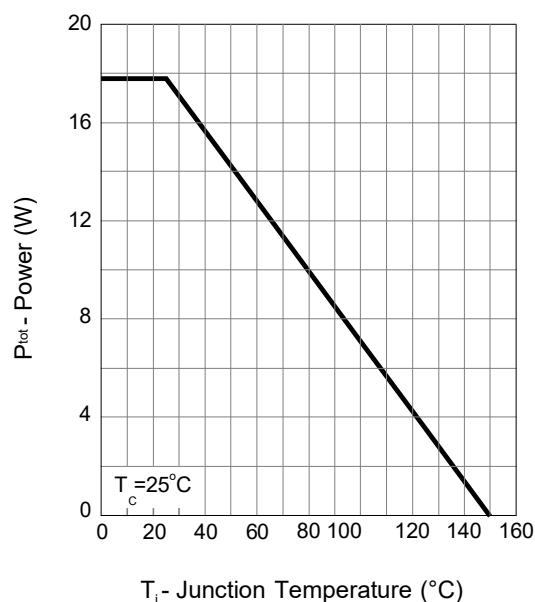
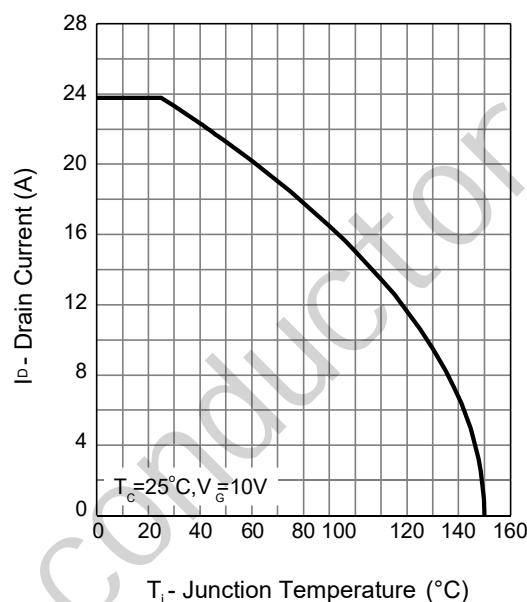
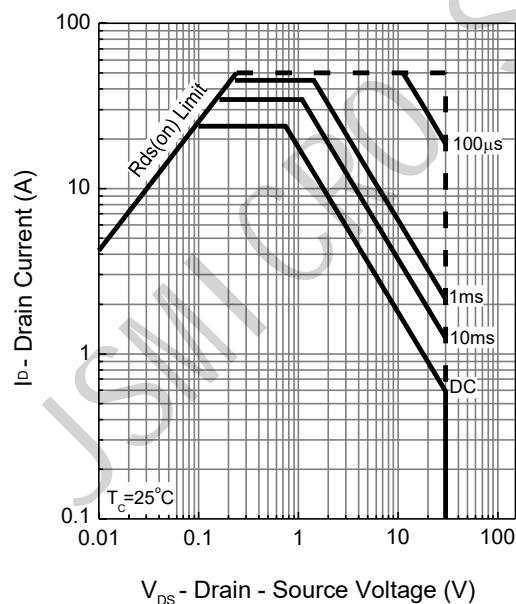
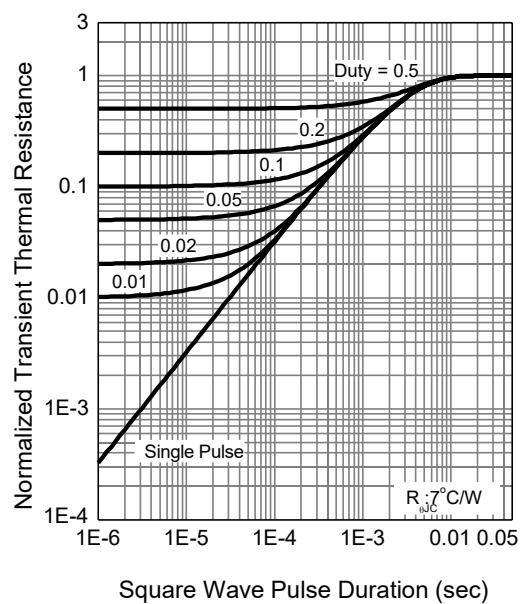
Note d: Pulse test ; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

Note e: Guaranteed by design, not subject to production testing.

Typical Operating Characteristics

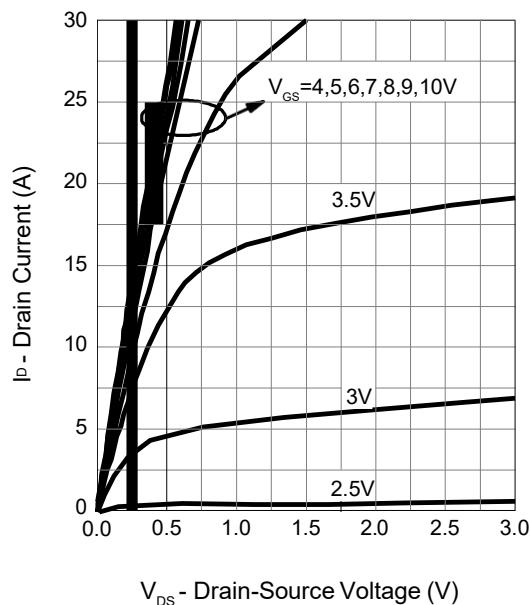
Power Dissipation

Drain Current

Safe Operation Area

Thermal Transient Impedance


Typical Operating Characteristics (Cont.)

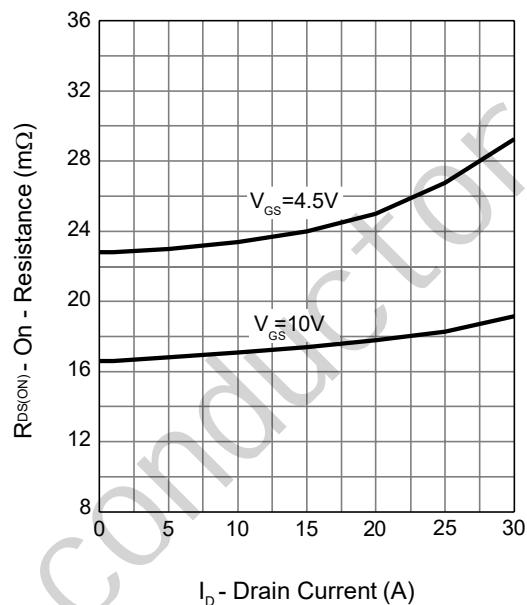
Power Dissipation

Drain Current

Safe Operation Area

Thermal Transient Impedance


Typical Operating Characteristics (Cont.)

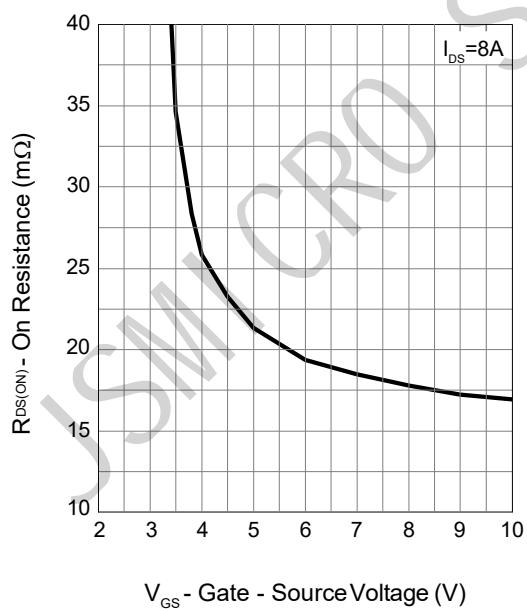
Output Characteristics



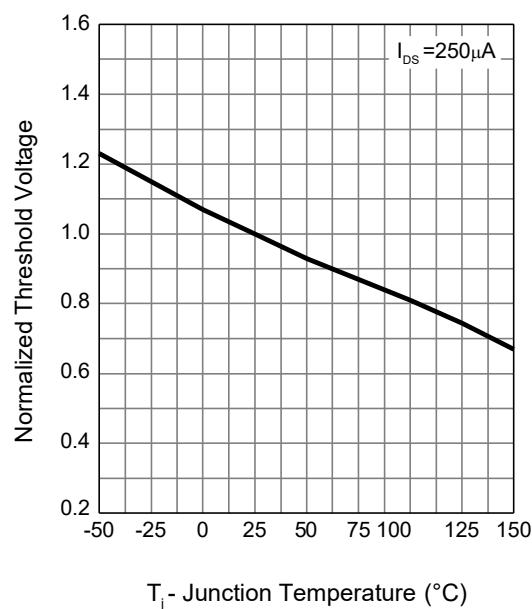
Drain-Source On Resistance



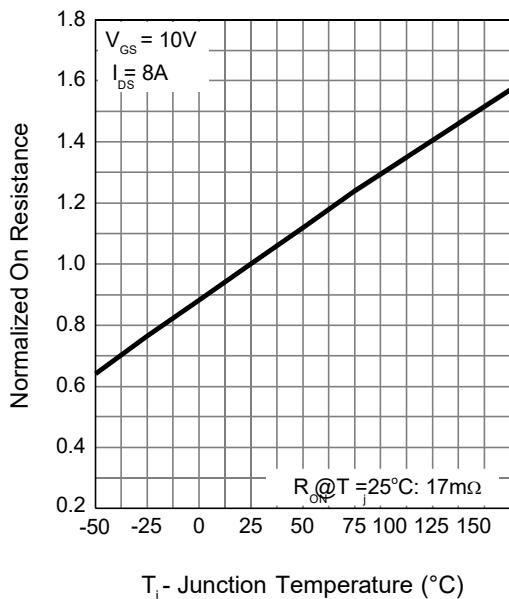
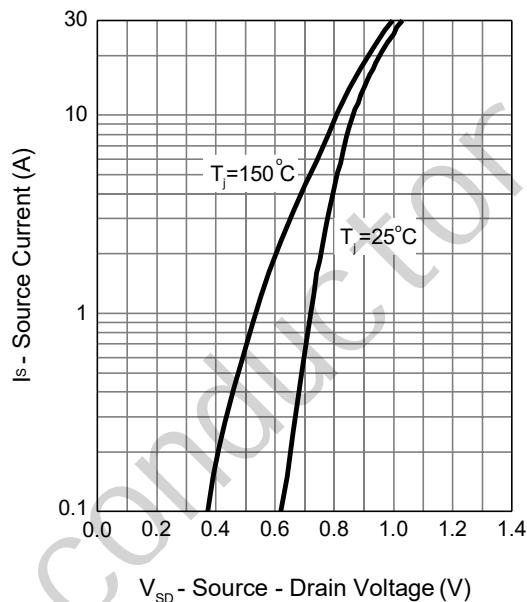
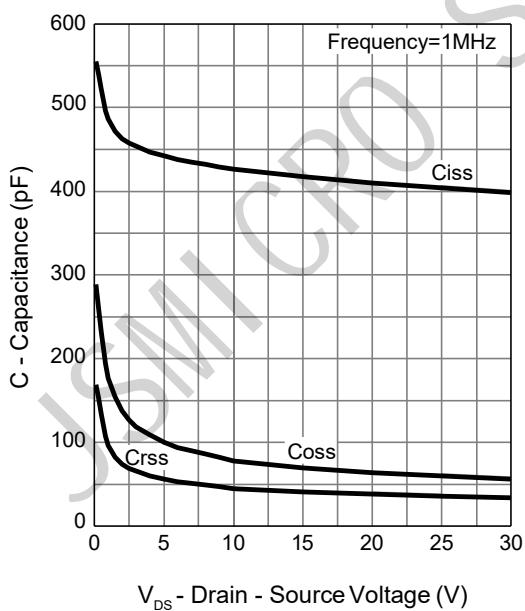
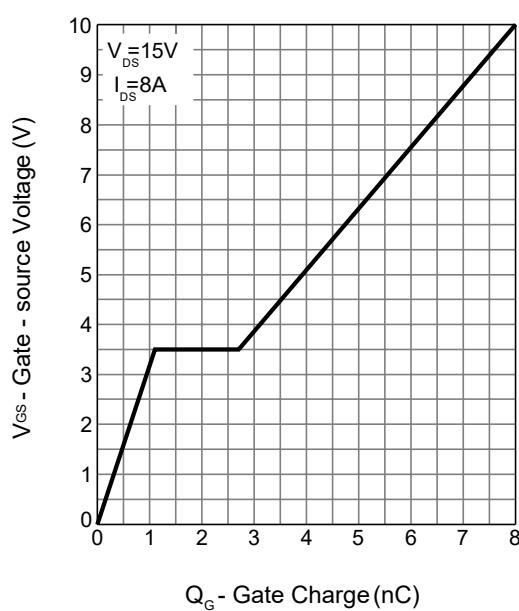
Gate-Source On Resistance

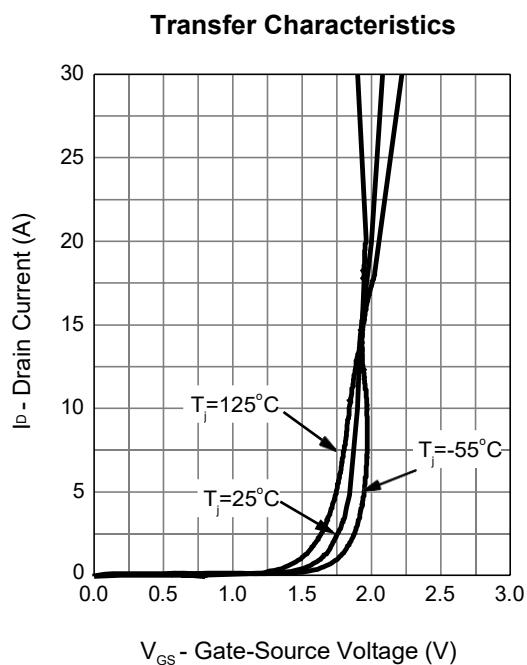


Gate Threshold Voltage

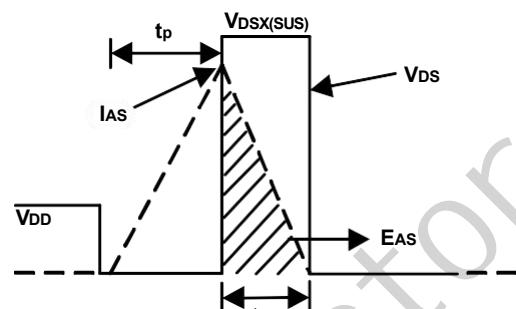
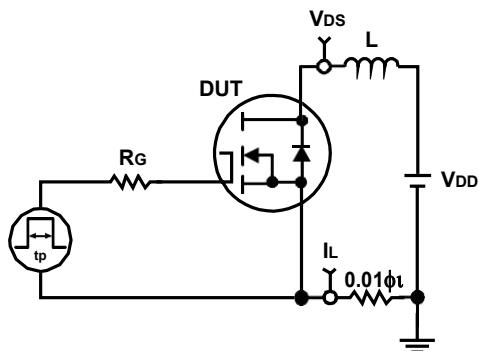


Typical Operating Characteristics (Cont.)

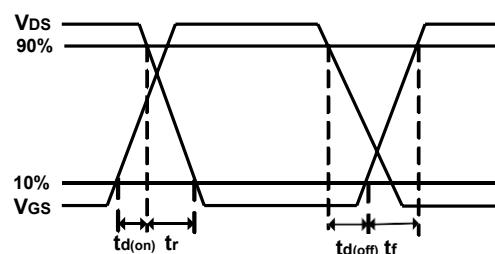
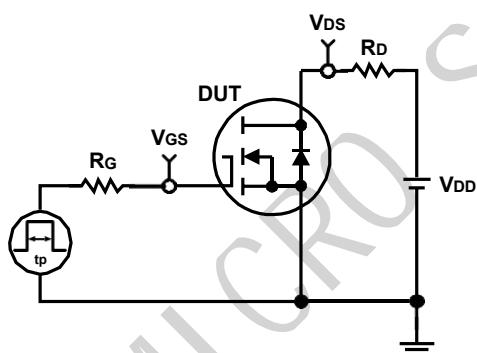
Drain-Source On Resistance

Source-Drain Diode Forward

Capacitance

Gate Charge


Typical Operating Characteristics (Cont.)

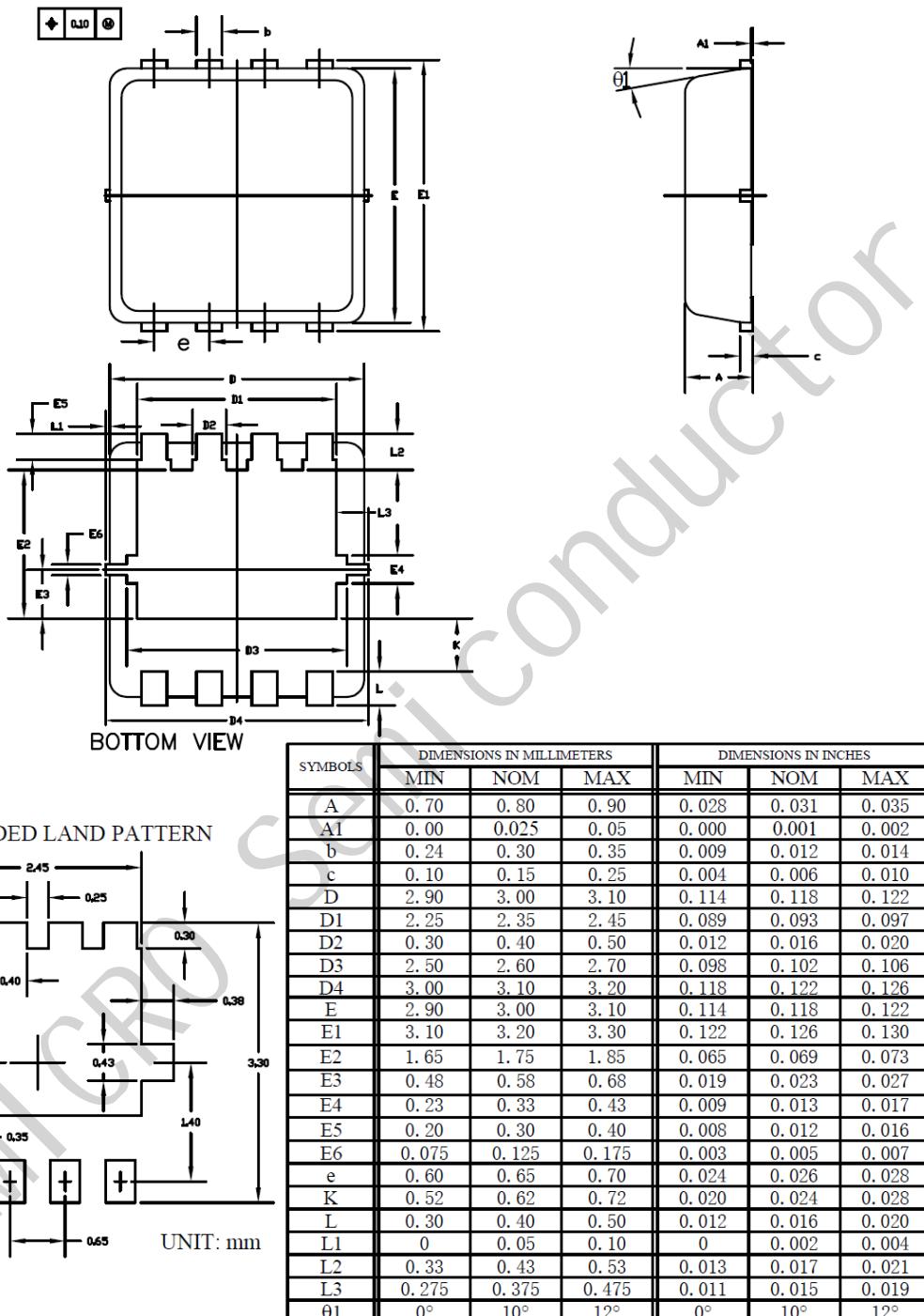
Avalanche Test Circuit and Waveforms



Switching Time Test Circuit and Waveforms



- Package Information



NOTE

1. PACKAGE DIMENSION IS EXCLUSIVE OF MOLD GATE BURR
2. PACKAGE DIMENSION IS EXCLUSIVE OF MOLD FLASH AND CUTTING BURR
3. CONTROLLING DIMENSION IS MILLIMETER.
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.